



SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION PTO-1449				ATTY. DOCKET NO. SUN04-0550-EKL		APPLICATION NO. 10/714,084	
				APPLICANT Hideya Kawahara, et al.			
				FILING DATE November 14, 2003		GROUP ART UNIT 2673	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
J-L	US2004/0090467 A1	May 13, 2004	Bonura et al.	345	790	11/5/03	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Dean Key</i>				DATE CONSIDERED 6/28/06			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
J.L.	5,774,125	Jun. 30, 1998	Suzuoki et al.	345	430	3/6/96	
J.L.	6,229,542	May 8, 2001	Miller	345	358	7/10/98	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
J.L.	GB 2 387 754 A	Oct. 22, 2003	Great Britian	G06T	15/10	X	
OTHER DOCUMENTS: (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Kean Key-ee</i>				DATE CONSIDERED 6/28/06			

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